

Product Change Notification - GBNG-06GBPZ091

Date:

12 Dec 2018

Product Category:

8-bit Microcontrollers; FPGA Configuration Memory

Affected CPNs:

|大||劉

Notification subject:

CCB 3640 Initial Notice: Qualification of MTAI as a new final test site for selected Atmel products available in 20L, 52L and 68L PLCC packages.

Notification text:

PCN Status:

Initial notification

PCN Type:

Manufacturing Change

Microchip Parts Affected:

Please open one of the icons found in the Affected CPNs section above.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

Description of Change:

Qualification of MTAI as a new final test site for selected Atmel products available in 20L, 52L and 68L PLCC packages.

Pre Change:

Tested at ANAP final test site.

Post Change:

Tested at MTAI final test site.

Pre and Post Change Summary:

	Pre Change	Post Change			
Final test site	Amkor Technology	Microchip Technology			
	Philippine (P1/P2), INC.	Thailand (HQ)			
	(ANAP)	(MTAI)			

Impacts to Data Sheet:

None

Change Impact:

None

Reason for Change:

To improve on-time delivery performance by qualifying MTAI as a new final test site.

Change Implementation Status:

In Progress

Estimated Qualification Completion Date:

February 2019

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.



Time Table Summary:

_	December 2018					February 2019					
Workweek	48	49	50	51	52	>	05	06	07	08	09
Initial PCN Issue Date			X								
Qual Report Availability											X
Final PCN Issue Date											X

Method to Identify Change:

Traceability code

Qualification Plan:

Please open the attachments included with this PCN labeled as PCN # Qual Plan.

Revision History:

December 12, 2018: Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachment(s):

PCN GBNG-06GBPZ091 Qual Plan.pdf

Please contact your local <u>Microchip sales office</u> with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our <u>PCN home page</u> select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the <u>PCN FAQ</u> section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

GBNG-06GBPZ091 - CCB 3640 Initial Notice: Qualification of MTAI as a new final test site for selected Atmel products available in 20L, 52L and 68L PLCC packages.

Affected Catalog Part Numbers (CPN)

AT17LV002-10JU

AT17LV002-10JU-T

AT17LV002A-10JU

AT17LV010-10JU

AT17LV010A-10JU

AT17LV256-10JU

AT17LV256-10JU-T

AT17LV512-10JU

AT17LV512-10JU-T

AT17LV512A-10JU

AT17LV512A-10JU-T

AT89C5130A-S3SUM

AT89C5131A-S3SUL

AT89C5131A-S3SUM

AT89C51AC3-S3SUM

AT89C51CC03CA-S3SUM

AT89C51CC03UA-S3SUM

AT89C51ED2-SMSUM



QUALIFICATION PLAN SUMMARY

PCN #: GBNG-06GBPZ091

Date December 01, 2018

Qualification of MTAI as a new final test site for selected Atmel products available in 20L, 52L and 68L PLCC packages.

Purpose: Qualification of MTAI as a new final test site for selected Atmel

products available in 20L, 52L and 68L PLCC packages.

CCB No.: 3640

Test / Evaluation	Test Conditions / Parameters	
Datalog / Bin Comparison	3,000-unit yield sample for bin comparison	
Yield Comparison	3,000 units matching to 0.1% yield	
Parametric Data Comparison	50 units of parametric data comparison	